

This comment is given based on my involvement as chair of the Legal Electronic Data Exchange Standards (LEDES) Oversight Committee's Intellectual Property Matter Management (IPMM) subcommittee. This comment is my own opinion and is not attributable to my employer or to the LEDES Oversight Committee.

Docket No.: PTO-P-2016-0006

Patent Quality Metrics for Fiscal Year 2017 and Request for Comments on Improving Patent Quality Measurement

If the "Master Review Form" questionnaire or similar form will be available to the applicant or to the public, please consider developing a standard XML document format rather than using an unstructured format. In particular, development of a schema using the XML Schema Definition (XSD) language would be optimal for data completeness, quality, and accessibility. An XML document would permit both the USPTO and recipients to process the contents more quickly, at lower cost, and with fewer errors. Both XML and XSD are open standards maintained by W3C. As an example of a schema developed for use with intellectual property, please see the LEDES Invention Disclosure standard found at <https://ledes.org/loc-ipmm-invention-disclosure-schema/>.

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